

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10829295	INOUE ET AL.
Examiner	Art Unit	
Jonathan R Beckley	4178	

SEARCHED			
Class	Subclass	Date	Examiner
379	100.07,100.04	11/20/2007	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13, 1.12	11/20/2007	JB
705	2,58,51,75,73,26,,71,43,64	11/20/2007	JB
348	231.9, 552,239,231.3,	11/20/2007	JB
380	54	11/20/2007	JB
709	206,223	11/20/2007	JB
715	839	11/20/2007	JB
718	102	11/20/2007	JB
382	233,100	11/20/2007	JB
400	61	11/20/2007	JB
700	241	11/20/2007	JB
434	350	11/20/2007	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13, 1.12	6/9/2008	JB
379	100.07,100.04	6/9/2008	JB
705	2,58,51,75,73,26,,71,43,64	6/9/2008	JB
348	231.9, 552,239,231.3,	6/9/2008	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13, 1.12	5/18/2009	JB
709	206,223	5/18/2009	JB

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST	11/19/2007	JB	
EAST	11/20/2007	JB	
CONSULTED WITH HAI TRAN	11/19/2007	JB	
EAST	6/9/2008	JB	
EAST	5/18/2009	JB	
EAST	5/16/2009	JB	
CONSULTED WITH TWYLER HASKINS	5/19/2009	JB	
CONSULTED WITH GARBIEL GARCIA	5/18/2009	JB	
CONSULTED WITH EIC (STIC)	5/18/2009	JB	
EAST	12/3/2009	JB	
CONSULTED WITH QEM	12/3/2009	JB	

/JONATHAN R BECKLEY/
Examiner Art Unit 2625

SEARCH NOTES

Search Notes	Date	Examiner
CONSULTED WITH CHAN PARK	12/3/2009	JB
CONSULTED WITH EDWARD ZEE	12/3/2009	JB
CONSULTED WITH BRANDON HOFFMAN	12/3/2009	JB
CONSULTED WITH TWYLER HASKINS	12/3/2009	JB

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
358	1.14, 1.15, 403	12/3/2009	JB
709	206, 223	12/3/2009	JB
380	243, 246	12/3/2009	JB
	SEE INTERFERNCE SEARCH I EAST SEARCH HISTORY	12/3/2009	JB

/JONATHAN R BECKLEY/
Examiner, Art Unit 2625